

Notice of References Cited	Application/Control No. 10/085,587	Applicant(s)/Patent Under Reexamination EBIHARA, HITOSHI	
	Examiner Po-Wei (Dennis) Chen	Art Unit 2676	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,434,714 B1	08-2002	Lewis et al.	714/38
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	C	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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